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AMENDMENTS TO THE CLAIMS

(The following includes a complete listing of all claims with their current status indicated. Additional language is underscored; deletions are stricken through.)

31. (Currently Amended) A local interconnect comprising:

a composite structure comprising a first metal silicide, a second metal silicide and an intermetallic compound ~~separating said first metal silicide from said second metal silicide~~ reducing the resistance of said local interconnect, wherein said intermetallic compound comprises metal from said first metal silicide and metal from said second metal silicide, wherein said intermetallic compound contains no non-metallic materials.

32. (Original) The local interconnect of claim 31, wherein said first metal silicide and said second metal silicide each comprise at least one refractory metal.

33. (Original) The local interconnect of claim 32, wherein said at least one refractory metal for said first metal silicide and said second metal silicide is selected from the group consisting of chromium, cobalt, molybdenum, nickel, niobium, palladium, platinum, tantalum, titanium, tungsten, and vanadium.

34. (Original) The local interconnect of claim 32, wherein said first metal silicide comprises titanium silicide and said second metal silicide comprises tungsten silicide.

35. (Currently Amended) A local interconnect for connecting a first active semiconductor region to a second active semiconductor region on a substrate assembly, said first and second active semiconductor regions being separated by an insulating region, said local interconnect comprising:

a composite structure comprising a first refractory metal silicide, a second refractory metal silicide and an intermetallic compound ~~separating said first refractory metal silicide from said second refractory metal silicide~~ reducing the resistance of said local interconnect, wherein said intermetallic compound comprises refractory

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metal from said first refractory metal silicide and refractory metal from said second refractory metal silicide, said refractory metal from said first refractory metal silicide being different from said refractory metal from said second refractory metal silicide, wherein said intermetallic compound contains no non-metallic materials.

36. (Original) The local interconnect of claim 35, wherein said composite structure has a thickness in the range of about 700 Angstroms to about 1800 Angstroms.

37. (Currently Amended) A semiconductor device comprising:

- a substrate assembly having at least one semiconductor layer;
- at least one field effect transistor formed in said at least one semiconductor layer, said at least one field effect transistor having a source, a drain and a gate; and
- a local interconnect for connecting at least one of said source, said drain and said gate to another active area within said substrate assembly, said local interconnect comprising a composite structure comprising a first refractory metal silicide, a second refractory metal silicide and an intermetallic compound ~~separating said first refractory metal silicide from said second refractory metal silicide~~ reducing the resistance of said local interconnect, wherein said intermetallic compound comprises refractory metal from said first refractory metal silicide and refractory metal from said second refractory metal silicide, wherein said intermetallic compound contains no non-metallic materials.

38. (Currently Amended) A memory array comprising:

- a plurality of memory cells arranged in rows and columns and formed on a substrate assembly having at least one semiconductor layer, each of said plurality of memory cells comprising at least one field effect transistor; and
- at least one local interconnect for connecting at least one of a source, a drain and a gate of said at least one field effect transistor in one of said plurality of memory cells to one of an active area within said one memory cell or to one of a source, a drain and a gate of said at least one field effect transistor in another one of said plurality of memory cells,

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said local interconnect comprising a composite structure comprising a first refractory metal silicide, a second refractory metal silicide and an intermetallic compound ~~separating said first refractory metal silicide from said second refractory metal silicide~~ reducing the resistance of said local interconnect, wherein said intermetallic compound comprises refractory metal from said first refractory metal silicide and refractory metal from said second refractory metal silicide, wherein said intermetallic compound contains no non-metallic materials.

39. (Original) The memory array of claim 38, further comprising a plurality of local interconnects for connecting additional active areas within each of said plurality of memory cells.

40. (Original) The memory array of claim 38, further comprising a plurality of local interconnects for connecting together active areas from different memory cells.

41. (Currently Amended) A local interconnect comprising:

a composite structure comprising a first metal silicide, a second metal silicide and an intermetallic compound formed by a reaction between said first metal silicide and said second metal silicide, wherein said intermetallic compound comprises metal from said first metal silicide and metal from said second metal silicide reducing the resistance of said local interconnect, wherein said intermetallic compound contains no non-metallic materials.